## Notice of References Cited Application/Control No. 10/014,310 Examiner Lois Zheng Applicant(s)/Patent Under Reexamination SHAH ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	В	US-			
	O	US-			
	D	US-			
	E	US-			
	F	US-			
	O	US-			
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	_	US-			
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	К	US-			
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	М	US-			

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	N	DD-268004	05-1989	Germany	Klose et al.	C22C 27/02
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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